Notice of References Cited

Application/Control No.

10/003,184

Examiner

Kandasamy Thangavelu

Applicant(s)/Patent Under
Reexamination
REBLEWSKI, FREDERIC

Art Unit
Page 1 of 2

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,777,489	07-1998	Barbier et al.	326/40
	В	US-6,265,894	07-2001	Reblewski et al.	326/39
	С	US-2004/0078187	04-2004	Reblewski, Frederic	703/028
	D	US-6,052,524	04-2000	Pauna, Mark R.	703/22
	Е	US-			
	F	US-			
	G	US-			
	Н	US-			
	ı	US-			
	J	US-		·	
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Ni et al., "A 256X256 pixel smart CMOS image sensor for line-based stereo vision applications", IEEE 2000.
	V	Miyake et al., "A gesture controlled human interface using an artificial retina chip", IEEE 1996
	w	Osterman et al., "Superconducting infrared detector arrays with infrared processing circuitry", IEEE 1991.
	x	Agusleo et al., "Employing logic-enhanced memory for high performance ATM network interfaces", IEEE 1996

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination REBLEWSKI, FREDERIC | Examiner | Art Unit | Page 2 of 2

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-			
	В	US-			
	С	US-			
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z					
	0					
	Р					
	σ					
	R					
	S					
	Т				·	·

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	υ	Vries et al., "Built-in self-test methodology for A/D converters", IEEE 1997.
	٧	Azais et al., "A low-cost adaptive ramp generator for analog BIST applications", IEEE, May 2001.
	w	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.